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Mobilities in high-quality CVD diamond crystals evaluated by time-offlight measurements: experimental and simulation results

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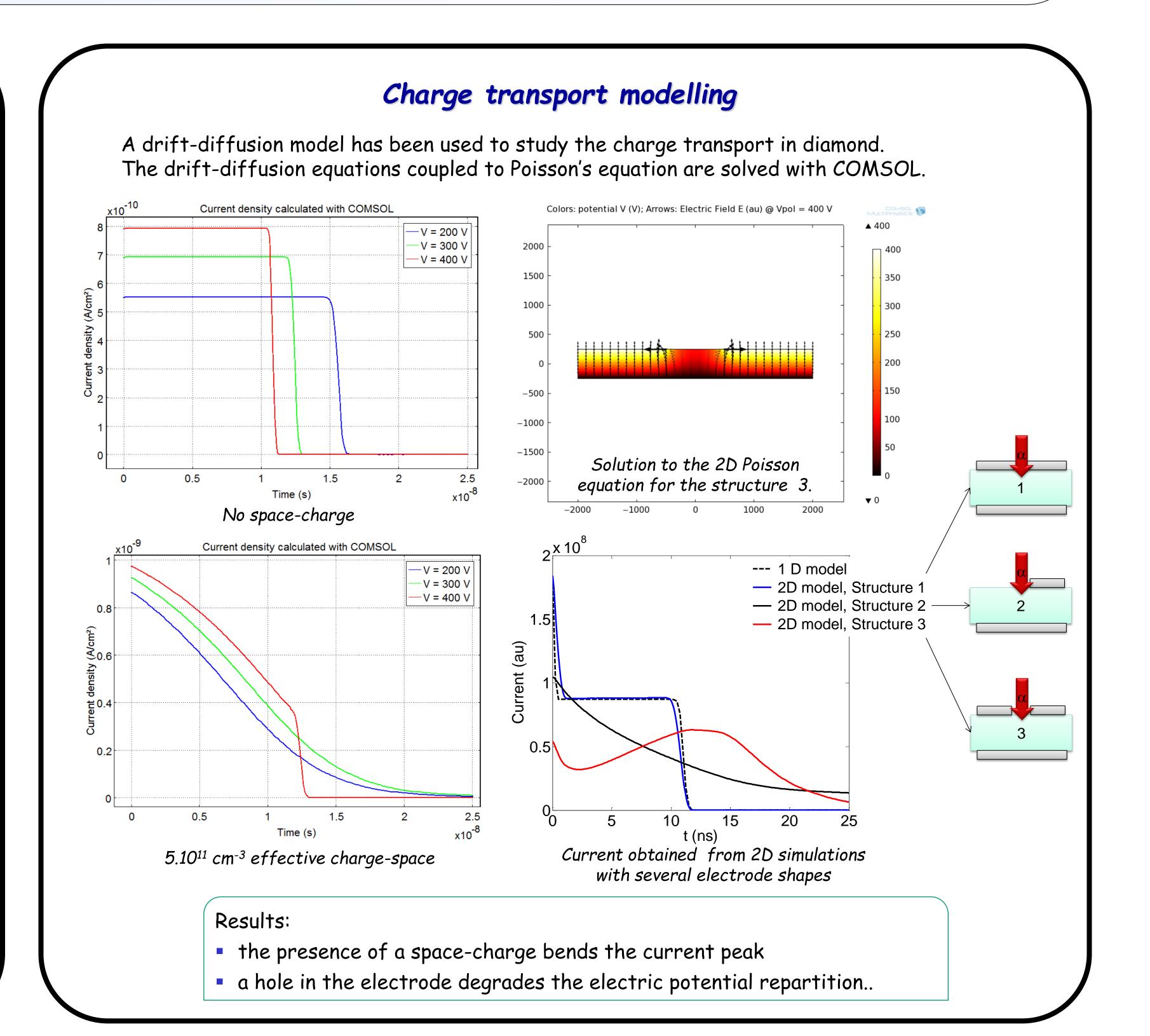
Abstract

Diamond is a promising candidate for power electronics as well as for radiation detection1. In both cases, device optimization requires an accurate knowledge of electron and hole mobilities.

In this study, time-of-flight (TOF) experiments were performed on intrinsic CVD diamond crystals to determine carrier mobilities. Electron-hole pairs were generated in a biased diamond layer by α rays. The resulting current peak was amplified and measured.

The distribution of electron-hole pairs in the sample has also been studied by means of simulation with SRIM and Geant4. This distribution has then been used to simulate the charge transport in the diamond. A drift-diffusion model, coupled with Poisson's equation, was implemented in COMSOL. These simulation tools have been used to optimize the sample and experimental setup geometry.

Radiation effect modelling Particle ranges have been calculated with SRIM. The full energy deposition profile have been calculated with Geant4 (with the Livermore energy model) which takes into account secondary electrons. Ranges calculated by SRIM Full geometry of the sample holder (green), with the sample (diamond in gray, Al in yellow) modeled in Geant4. Electrode thickness (nm) Depth-dose profile calculated with the Geant4 toolkit Depth vs. Z-Axis Range calculated by SRIM-Tracks of 100 lpha-rays calculated with SRIM (left) and Geant4 (right, with α particles in yellow and secondary electrons in blue). Depth (µm) Results obtained with a 250 nm-thick Al electrode: • Range = $13.4 \, \mu \text{m}$



Time-of-Flight measurements

Electron-hole pairs are generated on one side of the sample with alpha rays from an 241 Am source.

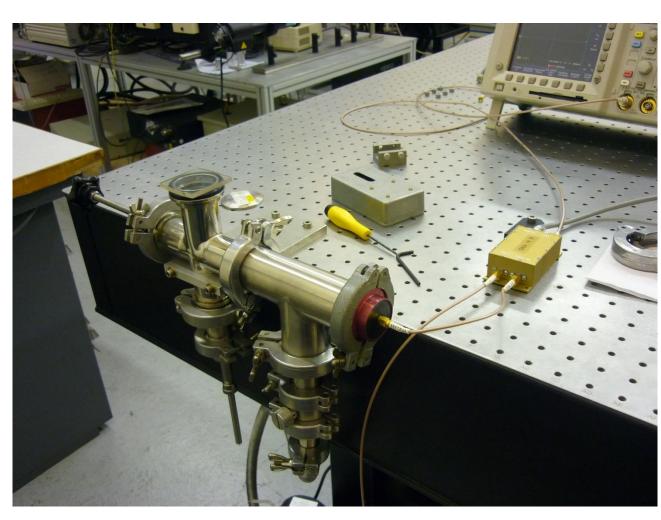
The sample is biased with a Keithley 6487 used as a DC voltage generator to collect electrons and holes and the obtained current is amplified by a DBA-IV/R device.

The amplified current is finally measured with a Tektronix TD5300 oscilloscope.

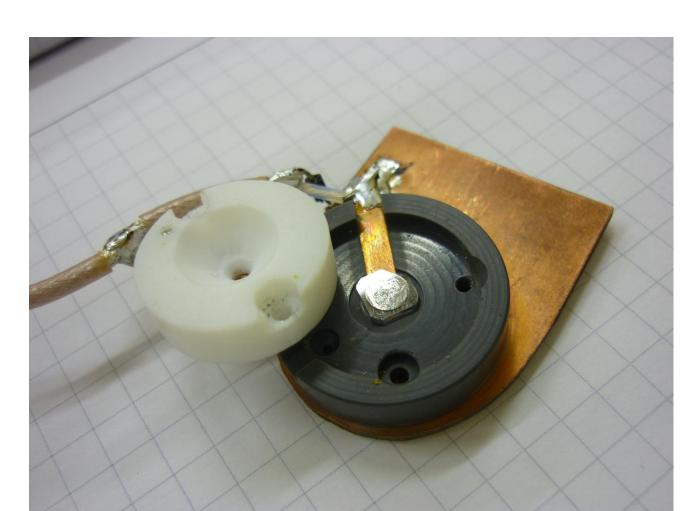
99.3 % of the energy is deposited in the diamond layer

• 0.4 % of α particles hit the diamond

The sample is a 620μ m-thick intrinsic freestanding CVD diamond film onto which 250 nmthick Al contacts were evaporated.



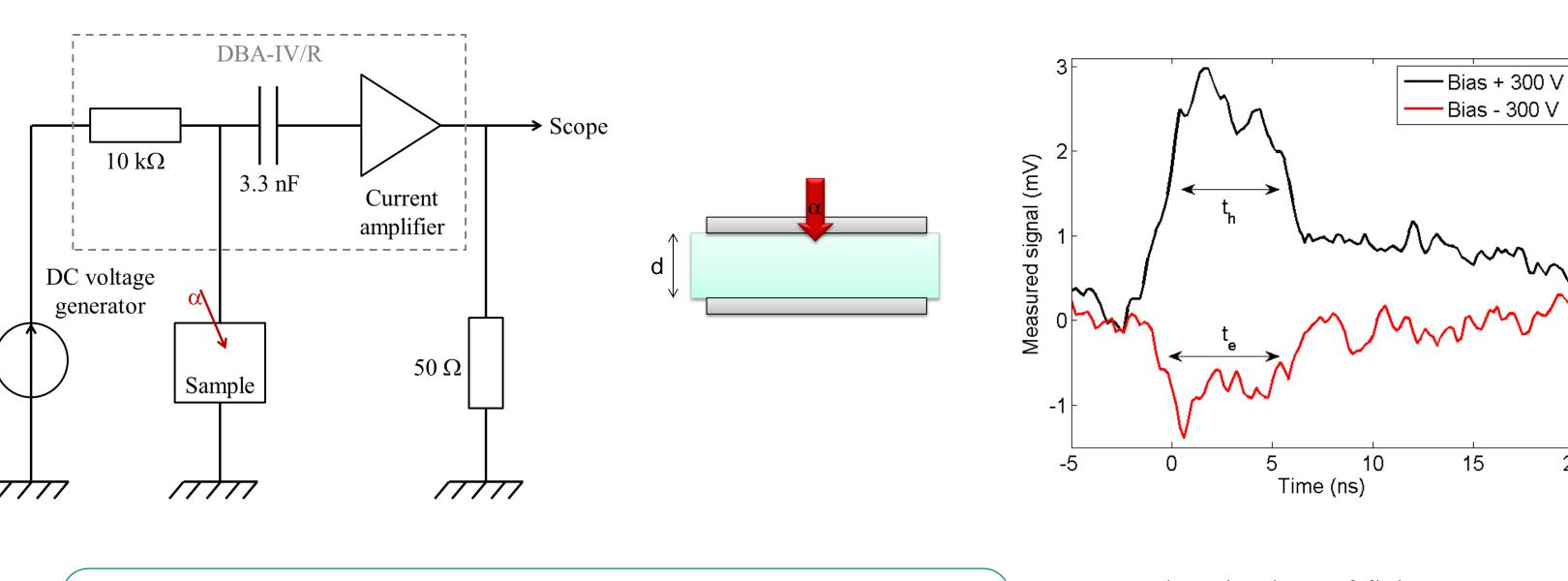
The experimental setup



The sample in the sample holder

The measured signal is a peak which full width at half maximum is the time-of-flight. The hole mobility μ_h and electron mobility μ_e are extracted from the measured time of flight t_h and t_e with

where E is the applied electric field and d the diamond thickness.



Results @ 300 V:

- Hole mobility of 2200 m²/Vs
- Electron mobility of 2200 m²/Vs

Measured signal and time-of-flight extraction

Conclusion

Time-of-Flight experiments have been performed. The experimental setup was studied by means of simulations.

The sample holder and the sample geometry have been studied. The effect of a particles in diamond and the charge transport have been modeled. Simulations show that the sample holder stops most of the particles while the electrode thickness is too low to have an influence on the energy deposition. The electrode geometry effect on the current measured have also been studied. This shows that a thin full plate electrode covering the sample is needed.

First measurements have shown a good electron and hole mobility in diamond. The experimental setup will be improved thanks to our simulation results to obtain more results.